

Index

a

ab-initio total energy
 – formation of 493–494
 – overview of 483
 absorptance 6, 9, 10, 11, 28, 48, 53,
 55, 56, 58
 absorption coefficient 10, 11, 12, 20, 65,
 67, 180
 absorptivity 153, 170
 activation energy 44–46, 89, 94
 Adiabatic local density approximation
 484
 admittance 81
 admittance spectroscopy 81, 95–97
 AFORS-HET 521, 522
 AM1.5 spectrum 6, 42, 516, 533
 ambipolar transport 181
 amorphous fraction 381
 amphoteric 251
 amphoteric state 504
 amplitude modulation 279
 AMPS-1D 522
 angle distribution functions 520
 angle-dispersive X-ray diffraction 357
 angularly resolved scattering 114, 116,
 120, 121
 annular dark-field detector 327
 anomalous dispersion 219
 anti-Stokes band 368
 anti-Stokes process 369
 APSYS 531
 Arrhenius dependence 460
 Arrhenius plot 94
 ASA 13, 523
 ATLAS 531
 atomic force microscope 110, 275
 atomic force microscopy 318
 – conductive 276, 279

– non-contact 278
 attempt-to-escape frequency 221
 Auger electron spectroscopy 411, 427
 Auger electrons 301
 Auger process 427, 428
 Auger recombination 16
 autocompensation 254

b

back surface field 292
 backscattered electrons 300
 band alignment 399, 400,
 403, 404
 band bending 13, 14, 88, 285,
 288, 289
 band diagram 291
 band-gap energies 496
 band-gap fluctuations 9
 band-tail width 220
 band-band transitions 163
 bandtail. *see* tail
 Bethe–Salpeter equation 484
 bilayer process 21
 bimolecular recombination 258
 biplate 130
 black body spectrum 41
 black body 6, 63
 Boeing process 21
 Bohr magnetron 232, 234
 Bragg diffraction 306, 327,
 332, 336
 Bragg's law 351
 bremsstrahlung 333, 334
 Bruggeman effective medium
 approximation 136
 built-in electric field 14, 15, 19, 24, 26, 28,
 212, 286
 built-in voltage 82, 213, 227

c

capacitance 81, 210
 – dc 82
 – differential 82
 capacitance-voltage measurement 281
 capacitance-voltage profiling 81
 capture cross section 17, 82, 94, 509, 510, 512, 533
 capture rate 86
 carrier collection
 – voltage dependent 15
 carrier lifetime 181
 cathodoluminescence image 312
 cathodoluminescence 305, 312, 536
 CdCl₂ activation 24
 Chandezon method 114
 charge extraction 10, 12–14, 18, 19
 chemical bath deposition 21
 close space sublimation 315
 co-evaporation 21
 coherence length 130
 coincidence-site lattice 305
 collection function 308–311
 collection probability 5, 49
 COMSOL 531
 concentric hemispherical analyser 429
 conduction band 492
 conductive AFM *see* atomic force microscopy, -conductive
 confocal microscope 155
 continuity equations 501, 521, 532
 conventional TEM *see* transmission electron microscopy, -conventional
 convergent-beam electron diffraction 329
 Curie law 249, 252
 current/voltage curve 35, 83
 cylindrical mirror analyser 429

d

dangling bond 4, 26, 193, 231, 503
 dark conductivity 184
 dark current density 36
 Debye length 86, 290
 deep level optical spectroscopy
 98, 99
 deep level transient spectroscopy
 81, 95, 462
 deep state 81
 defect 16, 27, 37, 39, 52, 180, 194, 207, 231, 285, 288, 365, 377, 504–507, 512, 514, 521–524, 533
 – metastable 27
 defect-pool model 504–507
 demarcation energy 89, 206, 222

density of states 81, 89, 178, 198, 221, 222, 225, 257, 502, 503, 507, 508
 – hydrogen 462, 463, 471
 – phonon 381
 density-functional perturbation theory 486
 density functional theory 244, 251, 269, 480
 – band-gap problem of 483
 – basis sets 480, 481
 – Hohenberg–Kohn theorem 480
 – Jacobs ladder of 482
 – Kohn–Sham method 480
 – local-density approximation/generalized gradient approximation functionals 481–483
 – material properties 485–486
 – time-dependent 484
 –– adiabatic local density approximation 484
 depletion approximation 85
 desorption 450, 454, 455, 459, 462, 463, 468
 detailed balance 6, 9, 10, 87, 509
 deuterium 454
 diamagnetic 257
 dielectric constant 180, 533
 dielectric function 128, 133
 dielectric relaxation time 187, 209, 217
 diffraction 112
 diffraction pattern 325
 diffusion coefficient 181, 185
 – hydrogen 460
 diffusion constant 309
 diffusion length 14, 26, 65, 69–71, 109, 177, 181–186, 191, 195, 197, 291, 308–312, 321
 – hydrogen 456
 diode equation 7, 531
 diode-quality factor 531. *see also* ideality factor
 direct semiconductor 10
 disorder activated modes 377
 disorder 81
 dispersion
 – optical 126
 dispersion parameter 220
 dispersion 205
 – anomalous 206
 dispersive transport 206
 displacability 217, 225
 displacement current 205
 donor-acceptor pair recombination 160
 drive-level capacitance profiling 81, 97

e

effusion 449–472
 Einstein relationship 435
 electrically detected magnetic resonance 232, 264
 electrodeposition 374, 375
 electroluminescence 61, 264, 522
 electron backscatter diffraction 288, 302, 322
 – pattern 302–304, 322, 323
 electron beam induced current 307, 530
 electron density 480
 electron energy-loss spectroscopy 323, 329
 electron gas 480
 electron holography 335
 electron microscopy 299–345
 electron paramagnetic resonance 231
 electron spin resonance 231, 507
 electron-beam induced current 307, 530
 electronegativity 421
 electronic structure methods 483
 electron-nuclear double resonance 238
 electron-spin echo envelope modulations 238
 ellipsometry 125
 energy-dispersive X-ray diffraction 291, 334, 358, 418
 energy-dispersive X-ray elemental distribution maps 323
 energy-filtered transmission electron microscopy *see* transmission electron microscopy, -energy-filtered
 energy-loss near-edge structure 332
 enthalpy 459
 entropy 459
 equivalent circuit 41, 531
 equivalent circuit modeling 531
 evanescent light 109, 113
 exact numerical inversion 133
 exchange-correlation energy 481
 exciton 5, 313
 excitonic 144, 158
 extended energy-loss fine-structure 333

f

fast Fourier transformation 109, 118
 Fermi energy 81, 82, 95, 97, 491
 Fermi level 39, 45, 178, 194, 207, 231, 252, 257, 284, 285, 309, 469
 Fermi's golden rule 151, 392, 393
 Fermi–Dirac distribution 509
 finite-difference time-domain 116
 flatband 13–15
 fluorescence 372
 focused ion beam 305, 341

four point probe technique 41
 Fourier analysis 130
 Fourier coefficients 130
 Fourier transform 85
 Fourier-ratio deconvolution 333
 free energy 459
 free bound transition 159
 frequency modulation 279
 Fresnel fringes 337
 Fresnel's coefficients 519
 full potential linearized augmented plane wave method 481

g

Gaussian/numerical atomic orbital basis function 481
 generalized gradient approximation 481
 generalized Kirchhoff's law 153
 generalized Planck's law 153
 generation function 48
 gettering 291
 Gibbs free enthalpy 100
 glow discharge mass spectroscopy 411, 413, 417, 418
 glow-discharge optical emission 411, 413
 glow-discharge optical emission spectroscopy 416, 418
 goniometer 188
 grain boundary 288, 305, 311, 530
 grating 112, 179, 187
 grazing incidence X-ray diffraction 354
 Green–Kubo formalism 485
 gyromagnetic ratio 232

h

Hall effect 288, 289
 Hall measurement 203
 Hamaker constant 277
 Hamiltonian 240, 241
 Hartree–Fock calculation 251
 Hartree–Fock exchange 482
 Hartree–Fock method 482
 haze 114
 Hecht plot 213
 high angle annular dark field 327
 high injection condition 152
 Hooke's law 277
 hopping 205, 264, 265, 268
 Hough space 304
 Hubbard model 482
 hydrogen dilution 137
 hydrogen passivation 4
 hydrogen 449, 450, 453, 454, 456–472
 hyperfine interaction 233, 234, 240

i

ideality factor 37, 38, 39, 44
 inelastic scattering 388
 interface recombination 44
 interfacial barrier 47
 interference 11, 48, 50, 54, 55, 115, 118,
 178, 348, 349, 351, 519, 520
 intrinsic carrier concentration 502
 inverse photoelectron spectroscopy 390, 391
 ion bombardment 433, 436
 ion-beam sputtering 427, 433

k

Kelvin probe force microscope 276, 282
 Kelvin probe technique 275
 Kikuchi pattern 302
 Kirchhoff's law 6
 – Würfel's generalization 6
 Kohn–Sham framework 486
 Kramers–Heisenberg formalism 392, 393
 Kramers–Kronig rule 133
 Kramers–Kronig transformation 96

l

Lambert–Beer law 355, 521
 Lambertian distribution 10
 Landé factor 232
 Laplace transform 226
 Larmor frequency 245
 laser 70, 209, 370
 – dye 209
 – gas 370
 – solid state 371
 least squares regression 134
 lifetime 14, 37, 40, 57, 152, 186, 533, 538
 light beam induced current 530
 light scattering 109
 light trapping 4, 10, 11, 12, 18, 19, 109,
 116, 519
 light-induced degradation 194, 248, 257
 light-induced electron spin resonance 237
 light-soaking 195
 local density approximation
 – ZnO, point defects, formation
 energies 494
 localised vibrational modes 377
 long-range order 207
 Lorentzian broadening 143
 LO-TO splitting 370, 374
 low pass filter 83

m

magnetic moment 232, 240, 249
 many-body perturbation theory 484

Maxwell–Boltzmann approximation 502
 mean-inner potential 337
 Meyer–Neldel rule 97, 99
 Miller indices 350
 mobility edge 219
 mobility gap 25, 502–504, 507
 mobility 9, 14, 15, 17, 20, 25, 26, 27, 36, 81,
 180, 185, 186, 205, 212, 231, 252, 254, 255,
 258, 265, 502–504, 506, 507
 mobility-lifetime product 178
 molecular dynamics simulations 485
 monolayer 130
 Monte Carlo simulation 309
 Mott insulators 482
 multidimensional modeling 529
 multijunction solar cell 51, 68
 multiple-trapping model 215, 219

n

near-field scanning optical microscopy
 318
 neutron scattering 347–349, 351–354
 Newton–Raphson algorithm 133
 non-contact AFM *see* atomic force
 microscopy, -non-contact
 nuclear magnetic resonance 235
 numerical modeling 530

o

Ohm's law 180
 open-circuit voltage 7, 8, 15, 16, 17,
 20, 43, 46, 513, 514
 optical beam induced current 530
 optical near-field 109
 optical transitions 151, 158
 ordered vacancy compound 375
 oxygen vacancy 489

p

paramagnetic 231, 232, 237, 239, 241–246,
 248, 251, 252, 254, 255, 257, 260, 261, 263,
 264, 268
 parasitic absorption 48, 57
 passage effect 236, 238
 Pauli principle 252, 265
 PC1D 523
 percolation theory 507
 phase locked loop 279
 phasor diagram 82
 photoluminescence calibration 156
 phonon 367
 photocapacitance measurement 81, 98
 photoconductivity 178
 photocurrent 7, 12, 36, 37, 40, 41, 52, 55, 58

- photocurrent decay 205
 photoelectron spectroscopy 291, 388, 390
 photoluminescence 151, 264, 313
 – micro-PL 171
 photoluminescence setup 154
 photomultiplier tube 129, 372, 415
 photon flux 153
 photothermal deflection spectroscopy 55
 physical vapour deposition 374
 plasma enhanced chemical vapor
 deposition 135
 plasmon 428
 point defects
 – *ab-initio* characterization of 486–488
 – case study
 – in ZnO 494–496
 – formation energies of 493, 494
 – formation process 490
 – Gibbs free energy 488
 – Kröger–Vink notation of 489
 – thermodynamics of 488–493
 – vs. Fermi energy 494
 Poisson equation 92, 177, 336,
 501, 532
 polarization 180, 188, 366, 367, 374
 – optical 125
 Poole–Frenkel effect 94
 post-transit 206, 223
 potential fluctuations 162
 pre-transit 206
 profilometer 425
- q**
- quadrupole 421, 422, 450
 quantum efficiency of solar cell 47–56, 58,
 63–66, 292, 536
 – of a light emitting diode 66, 68
 quantum Monte Carlo method
 484
 quasi-Fermi level 38, 94, 111, 502
 quasi-Fermi level splitting 152, 153
- r**
- radiative lifetime 152
 Raman cross section 371
 Raman scattering 367
 Raman spectroscopy 365
 Rayleigh scattering 367
 RC time constant 518
 reciprocity 62, 63, 65, 66
 recombination 36–39, 41, 44–48, 52,
 55, 57, 58, 61–66, 68–71, 194, 291, 313,
 501, 502, 507–513, 521, 522, 533
 recombination center 81
 recombination current density 36
 reflection 10, 12, 18, 19, 48, 54
 refractive index 10, 112, 126, 179,
 355, 520
 relative sensitivity factor 417
 remote electron beam induced current
 307
 resonant inelastic X-ray scattering
 390
 reverse bias deep level transient
 spectroscopy 95
 Rietveld analysis 351, 352, 353
 Ritter–Zeldov–Weiser analysis 181
 Rutherford scattering 327
- s**
- SAED. *see* selected-area electron diffraction
 saturation current density 36, 39, 46
 Savitzky–Golay filter 430
 scanning capacitance microscopy 280
 scanning electron microscopy 299–323
 scanning near-field optical microscopy 109
 scanning spreading resistance
 microscopy 280
 scanning tunneling microscopy 275, 284,
 318, 530
 SCAPS 90, 513, 523, 524
 scattering cross section 347, 349
 Scherrer equation 360
 Schrödinger equation 479
 – *ab-initio* methods 479
 – Hamiltonian of 479
 SC-Simul 524
 secondary electrons 300, 388
 secondary ion mass spectrometry
 411, 420, 454
 secondary neutral mass spectrometry 422
 selected-area electron diffraction
 327, 328
 selenisation 21
 Sentaurus 531
 series resistance 37, 39, 40, 42–44, 70,
 71, 75, 77, 83
 Sah and Shockley statistics 523
 shallow state 81
 sheet resistance 73–77
 Shockley–Queisser theory 5, 7, 36, 47
 Shockley–Read–Hall recombination
 14, 37, 52, 508
 short-circuit current density 6, 7, 12, 14, 15,
 17, 36, 40, 42–44, 46, 47
 shunt 40, 44, 72, 75–77, 531
 Snell's law 128, 179
 solar simulator 42

- space charge region 13, 37–39, 41, 45
 - spatial inhomogeneities 170
 - spectral absorptivity 153
 - spectral response 47, 52
 - spectroscopic ellipsometry 48, 125
 - spectrum imaging 314
 - SPICE 40, 76, 531
 - spin 231–234, 236–241, 243–246, 248–252, 254, 255, 264–266, 268, 269
 - spin-lattice relaxation time 234
 - spin-orbit interaction 241
 - spontaneous emission rate 152
 - sputter deposition 21
 - sputtered neutral mass spectroscopy 411
 - S-shape 15
 - Staebler–Wronski effect 27
 - steady-state photocarrier grating 177
 - stoichiometric defect reaction 491
 - Stokes process 369
 - strain 365
 - stray light 372
 - substrate 18, 19, 20, 21, 22, 26
 - superposition principle 52
 - superposition 7
 - superstrate 4, 18, 19, 26
 - surface photovoltage 522
 - surface recombination 14–18, 184, 193, 502
 - surface recombination velocity 65, 69, 309, 310, 502
 - susceptibility tensor 374
 - susceptibility 366
 - synchrotron radiation 387, 390
- t**
- tail 9, 16, 71, 81, 184, 195, 252, 503, 504, 507
 - tandem cell 51, 52
 - temperature-programmed desorption 450
 - texture
 - geometric 109
 - thermal desorption spectroscopy 450
 - thermal velocity 17, 87, 502
 - thermalization 5, 27
 - thermodynamic stability 487
 - three-stage process 21
 - time-dependent density functional theory *see* density-functional theory, -time-dependent
 - time-of-flight 203
 - time-of-flight mass spectrometer 416
 - time-resolved photoluminescence 536
 - topography 111, 112, 120, 278, 283, 311
 - total internal reflection 10, 109, 113
 - transient photocapacitance spectroscopy 99
 - transit time 205, 206, 214, 216
 - transmission electron microscopy 323–338
 - bright-field 324
 - conventional 323, 340
 - dark-field 324
 - energy-filtered 329
 - high resolution 326
 - scanning 323, 324
 - transparent conductive oxides 23
 - trap 38, 81, 87, 93, 205, 219, 220, 223, 231, 280, 285, 288, 313, 508–510, 512, 521
 - trapped charge 180, 184
 - trap state 81
 - tripod polishing 340
 - tritium 454
 - tunneling luminescence microscopy 319
 - tunnelling enhanced recombination 38
 - two-diode model 39
 - type inversion 25
- u**
- Urbach energy 504
 - UV photoelectron spectroscopy 390
- v**
- van der Waals force 276
 - virtual interface analysis 133, 134, 136
 - void 461, 466, 469–471
- w**
- wavelength-dispersive X-ray spectrometry
 - see* X-ray spectrometry, -wavelength-dispersive
 - work function 282, 286, 288, 291, 435, 436
- x**
- X-ray absorption spectroscopy 390, 391
 - X-ray diffraction 286, 328, 350, 354, 357, 358, 373, 376, 378
 - X-ray emission spectroscopy 389, 390
 - X-ray excited Auger electron spectroscopy 390

X-ray fluorescence 334, 358, 391,
436, 441

X-ray photoelectron spectroscopy
390, 411, 435

X-ray scattering 347, 348

X-ray spectrometry

– energy-dispersive 306, 411, 440

– wavelength-dispersive 306, 353

X-rays 347–359, 387

z

Z contrast imaging 302, 327

Zeeman levels 232, 244

